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5.NO.	Product /	Specific Test Performed	Test Method Specification	Range of Testing /
	Material of Test		against which tests are	Limits of Detection
			performed	

## I. MEDICAL DIAGONISTIC EQUIPMENT

1.	MEDICAL ELECTRICAL EQUIPMENT	Tests of Effect of Voltage Dips and Short Interruptions	IEC60601-1-2:2001, 2007	At 63.5 V, 110 V & 240 V
	AND MEDICAL ELECTRICAL SYSTEMS	Power Frequency Magnetic Field	IEC 61000-4-8: 2001 IEC60601-1-2:2001, 2007	Upto 1000 AT / 0.2 T
	51512/45	Electrical Fast Transient Burst Test	IEC60601-1-2:2001, 2007 IEC 61000-4-4: 1995, 2004, 2012	0.5 kV to 7.0 kV 5 ns 50 ns
		Immunity to Electrostatic Discharges	IEC 61000-4-2: 1995, 2008 IEC60601-1-2:2001, 2007	0.2 to 15 kV Contact: 8 kV Air : 30 kV
		Surge Immunity Test	IEC 61000-4-5: 1995, 2005 IEC60601-1-2:2001, 2007	0.5 kV to 12 kV 1.2/50 us 8 /20 us
		Test of Immunity to Conducted Disturbances, Induced by Radio Frequency Fields	IEC60601-1-2:2001, 2007 IEC 61000-4-6: 1996, 2008	150 kHz to 80 MHz 1V to 10 V
		Immunity to Electromagnetic HF Field using Anechoic Chamber	IEC60601-1-2:2001, 2007 IEC 61000-4-3: 2002, 2006	Frequency Range : 80 MHz to 3 GHz Field strength :- Upto 1V/m, 3V/m, 10V/m (3m) 30V/m (1m)

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MEDICAL ELECTRICAL EQUIPMENT	Radio Interference Measurement	IEC60601-1-2:2001, 2007 CISPR 11 :2004,2010 CISPR 14-1 : 2005,2009		ency Range:- MHz to 30 MHz
AND MEDICAL ELECTRICAL SYSTEMS		CISPR 22 :1997,2006, 200 EN 55011 : 2007	For p	ower line
		EN 550022 :2006		Frequency Range:- 30 MHz to 6 GHz
	Interruption of the power supply / Supply Mains to ME Equipment	IEC 60601-1:2005+A 1:201		20V, 47 to 63 Hz 000V DC
	Excessive temperatures in ME Equipment		-40°C	to 1300°C
	Protective earthing, functional earthing and potential equalization of ME Equipment		0.3ms	Ω onwards
	Protection against electrical Hazards from ME Equipment		Upto	10kV (AC)
	Insulation			Upto 100MΩ voltage:
	Creepage Distances and Air Clearances			500V DC
	Components and wiring			

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MEDICAL ELECTRICAL EQUIPMENT AND MEDICAL	Accuracy of controls and instruments and protection against hazardous outputs	IEC 60601-1:2005+A 1:201	2 As pe	r standard
ELECTRICAL SYSTEMS	Hazards associated with moving		Upto	50 kg
	parts Fire prevention/ Constructional requirements for fire Enclosures of ME Equipment		0 to 1 180 m	00 N nm depth
	Leakage Currents and Patient		0 to 1	00 mA
	Auxiliary Currents Hazardous Situations and fault conditions		Upto	10kV
	ME Equipment components and general assembly (heating)		Ambi	ent to 140°C
	ME Equipment identification, marking and documents		-	
	Documentation		-	
	ingress of water or particulate matter, cleaning and dust test		Range IPX3, As pe	r IS12063 e:-IPX1,X2, X4 r IS12063 e:IP5X

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	MEDICAL ELECTRICAL EQUIPMENT AND MEDICAL ELECTRICAL SYSTEMS	Mechanical strength	IEC 60601-1:2005+A 1:201	UI -40	02 Nm to 10Nm pto 100°C 0 to 180°C 0 to 98%RH	
II. IN	NFORMATION TECI	HNOLOGY EQUIPMENT				
1.	INFORMATION TECHNOLOGY	Power interface Clause 1.6	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	24	0V, 120A	
	EQUIPMENT	Marking and instruction (Durability) Clause 1.7		Qu	ualitative test	
		Access to energized parts Clause 2.1.1.1		loi 44	0 mm ± 0.2 mm ng probe .04 mm ng Probe	
		Access to ELV wiring Clause 2.1.1.3			kV AC 200mm Vernier caliper	
		Access to hazardous voltage circuit wiring Clause 2.1.1.4		10	kV	
		Energy hazards Clause 2.1.1.5		lor rig Ste	0 mm ±0.2 mm ng jointed and gid Finger, op watch to 1000 s	

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	INFORMATION TECHNOLOGY EQUIPMENT	Manual controls Clause 2.1.1.6	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	10 kV	
		Discharge of capacitors in equipment Clause 2.1.1.7		-	
		Energy hazard Clause 2.1.1.8		2V, 20 AC VG wave) 200V, DC Cu 200 m AC Cu wave): 10 A Resista 20kΩ, 20MΩ Freque (3 V, s 20 kH:	bltage: 200mV, W, 200V, 1000V bltage- (50Hz, Sine 200 mV, 2V, 20V, 750V urrent: 20 mA, A, 10A urrent (50Hz, Sine 20 mA, 200 mA, ance: 200Ω, 2k Ω, 200 kΩ, 2MΩ,
		Audio amplifiers in IT equipment Clause 2.1.1.9 (IEC 60950-1:2006, A1:2013)		240V 1 kHz (signal	to 1.5GHz gen)

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	INFORMATION TECHNOLOGY EQUIPMENT	Protection in service access areas and Protection in restricted access locations Clause 2.1.2, 2.1.3	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	2V, AC way 200 DC 200 AC way 10A Res 20k 20N Free	Voltage: 200mV, 20V, 200V, 1000V Voltage: (50Hz, Sine 7e) 200mV, 2V, 20V, V, 750V Current: 20mA, mA, 10A Current: (50Hz, Sine 7e): 20mA, 200mA, A istance: 200Ω, 2kΩ, Ω, 200 kΩ, 2MΩ,
		SELV circuit Clause 2.2 (2.2.2, 2.2.3) TNV circuit Clause 2.3.1		240	V
		Protection by basic insulation Clause 2.3.2.2 Protection by earthing		10 I Ran	دV ige :
		Clause 2.3.2.3			ge : 5 V A to 40 V A

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INFORMATION TECHNOLOGY EQUIPMENT	Protection by other construction Clause 2.3.2.4 Connection of TNV circuits to other circuits Clause 2.3.4 Test for operating voltages generated externally Clause 2.3.5 Limit values (Annexure D)	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	10 kV 240 V 10 kV 10 kV 2 mA	
	Clause 2.4.2 Connection of limited current circuits to other circuits (Annexure D) Clause 2.4.3 Protective earthing Clause 2.6.1		2 mA 10 kV 10 kV	
	Size of protective earthing conductors Clause 2.6.3.2		0 to 20 Vernie	00 mm er Caliper
	Size of protective bonding conductor Clause 2.6.3.3		0 to 20 Vernie	00 mm er Caliper

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INFORMATION TECHNOLOGY EQUIPMENT	Resistance of earthing conductors and their terminations Clause 2.6.3.4	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	Range	: 32A, 0.1Ω
	Protective earthing and bonding terminals Clause 2.6.4.2		0 to 20 Vernie	0mm r Caliper
	Short-circuit backup protection Clause 2.7.3		10kV	
	Protection requirements Clause 2.8.2		jointed	h ±0.2 mm long l and rigid Finger, h+0.0, -0.1 Pin
	Inadvertent reactivation Clause 2.8.3		jointed	1 ±0.2 mm long 1 and rigid Finger, +0.0, -0.1 Pin
	Switches and relays Clause 2.8.7		0 to 20 Vernie	0 mm r Caliper
	Contacts gaps (Clause 2.8.7.1)		10kV	
	Overload test (Clause 2.8.7.2)		10kV	
	Endurance test (Clause 2.8.7.3) Electric strength tets			99900 cycles, e timer
	Clause 2.8.7.4			

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INFORMATION TECHNOLOGY EQUIPMENT	Properties of insulating materials and Humidity conditioning Clause 2.9.1, Clause 2.9.2	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010		o 95% RH C to +150°C Temp.
	Reduced values for functional insulation Clause 2.10.1.3			0mm nier Caliper
			10k	V
	Insulation in circuits generating starting pulses Clause 2.10.1.7			0mm nier Caliper
	Chause 2.10.1.7		10k	V
	General Clause 2.10.3.1		joint	$\pm 0.2 \text{ mm long}$ ted and rigid Finger, m+0.0, -0.1 Pin
	Clearances in primary circuits Clause 2.10.3.3			200 mm hier Caliper
	Clearance in secondary circuits Clause 2.10.3.4		10k <sup>1</sup>	-
	Clearances in circuits having starting pulses Clause 2.10.3.5 Transients from an a.c. mains			V to 12kV (surge)
	supply Clause 2.10.3.6			

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INFORMATION TECHNOLOGY EQUIPMENT	Transients from a d.c. mains supply Clause 2.10.3.7 Transients from telecommunication networks and cable distribution systems Clause 2.10.3.8 Creepage distances Clause 2.10.4.3 Distances through insulation Clause 2.10.5.2 Insulating compound as solid insulation Clause 2.10.5.3 Semi conductor devices Clause 2.10.5.4, Clause 2.10.5.5 Separable thin sheet material Clause 2.10.5.7 Thin sheet material -standard test procedure Clause 2.10.5.9 Thin sheet material - alternative test procedure Clause 2.10.5.10	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	10 kV 0 to 24	00 mm

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INFORMATION TECHNOLOGY	Insulation in wound components Clause 2.10.5.11	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	10 kV	
EQUIPMENT	Wire with solvent-based enamel in wound components Clause 2.10.5.12, 2.10.5.13		10 kV	
	Uncoated printed boards Clause 2.10.6.1			00 mm er Caliper
	Coated printed boards Clause 2.10.6.2		10 kV	
	Insulation between conductors on different surfaces of a printed board Clause 2.10.6.4			
	Thermal conditioning Clause 2.10.8.2			95% RH to +150°C Temp
	Electric strength test Clause 2.10.8.3		10kV	
	Thermal cycling Clause 2.10.9			98 %RH to +150°C

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INFORMATION TECHNOLOGY EQUIPMENT	Test for Pollution Degree 1 environment and for insulating compound Clause 2.10.10 Tests for semiconductor devices and for cemented joints Clause 2.10.11 Enclosed and sealed parts Clause 2.10.12 Current rating and overcurrent protection Clause 3.1.1 Insulation of conductors Clause 3.1.4 Beads and ceramic insulators Clause 3.1.5	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	-40 10 10 80 joi	kV 0 to 150 °C & $\pm$ 0.2°C kV N $\pm$ 1 N mm $\pm$ 0.2 mm long nted and rigid Finger, mm+0.0, -0.1 Pin
	Termination of conductors Clause 3.1.9 Multiple supply connections Clause 3.2.2 Appliance inlets Clause 3.2.4		M 0 t	o 25 mm icrometer o 200 mm ernier Caliper

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Power supply cords Clause 3.2.5 Supply wiring space Clause 3.2.9 Connection of non-detachable power supply cords Clause 3.3.2 Conductor sizes to be connected Clause 3.3.4 Wiring terminal sizes Clause 3.3.5 Wiring terminal design Clause 3.3.6 Stability Clause 4.1 Steady force test, 10 N	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	10°a Incli	N ± 10 N ngle ned plane setup ± 1 N	
Clause 4.2.2 Steady force test, 30 N Clause 4.2.3 Steady force test, 250 N Clause 4.2.4			± 3 N N ± 10 N	
	RIICO Bhamashah Inde ISO/IEC 17025: 2005 Electronics Testing T-2698 - Specific Test Performed Power supply cords Clause 3.2.5 Supply wiring space Clause 3.2.9 Connection of non-detachable power supply cords Clause 3.3.2 Conductor sizes to be connected Clause 3.3.4 Wiring terminal sizes Clause 3.3.5 Wiring terminal design Clause 3.3.6 Stability Clause 4.1 Steady force test, 10 N Clause 4.2.2 Steady force test, 30 N Clause 4.2.3 Steady force test, 250 N	RIICO Bhamashah Industrial Area, Kaladwas,         ISO/IEC 17025: 2005         Electronics Testing         T-2698         -         Specific Test Performed       Test Method Specificat against which tests are performed         Power supply cords       IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010         Supply wiring space       IS 13252 (Part1):2010         Connection of non-detachable power supply cords       IS 13252 (Part1):2010         Conductor sizes to be connected       Clause 3.3.2         Conductor sizes to be connected       Clause 3.3.4         Wiring terminal design       Clause 3.3.6         Stability       Clause 4.1         Steady force test, 10 N       Clause 4.2.2         Steady force test, 30 N       Clause 4.2.3         Steady force test, 250 N       Steady force test, 250 N	RIICO Bhamashah Industrial Area, Kaladwas, Udaipur, Ra         ISO/IEC 17025: 2005         Electronics Testing       Issue Date         T-2698       Valid Until         -       Page         Specific Test Performed       Test Method Specification against which tests are performed       Ran Limit         Power supply cords       IEC 60950-1:2005 A:2013       IS 13252 (Part1):2010         Supply wiring space       Clause 3.2.9       Connection of non-detachable power supply cords         Clause 3.2.9       Conductor sizes to be connected       State 3.3.4         Wiring terminal sizes       Clause 3.3.5       Stability       250 I         Clause 4.1       10° a       Incluse 4.1       10° a         Steady force test, 10 N       10 N       30 N       30 N         Steady force test, 30 N       30 N       30 N       30 N         Steady force test, 250 N       250 I       250 I	

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	INFORMATION TECHNOLOGY	Impact test Clause 4.2.5	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	:	500 g ±	± 25 g
	EQUIPMENT	Stress relief test Clause 4.2.7				5% RH to +150°C Temp.
		Wall or ceiling Clause 4.2.10		:	50 N ±	3 N
		Design and construction Except clause 4.3.12, 4.3.13			-	
		Handles and manual controls Clause 4.3.2		(	0 to 5 l	¢g
		Batteries Clause 4.3.8		j	jointed	±0.2 mm long and rigid Finger, +0.0, -0.1 Pin
		Dust, powders, liquids and gases Clause 4.3.10			0 to 20 Vernie	0 mm r Caliper
		Protection in operator access areas Clause 4.4.2		j	jointed	±0.2 mm long and rigid Finger, +0.0, -0.1 Pin

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	INFORMATION TECHNOLOGY EQUIPMENT	Temperature tests Clause 4.5.2	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	.3 20 to 98 %RH -40°C to +150°C			
	EQUIIMENT	Temperature limits for materials Clause 4.5.3		Glow 0 to 10	wire test setup 000°C		
		Touch temperature limits Clause 4.5.4					
		Resistance to abnormal heat Clause 4.5.5					
		Adhesives for constructional purposes Clause 4.6.5					
si		Electrical requirements and simulated abnormal conditions Clause 5.1		0.25 m 2 mA 500 m 15 mA			
		Electric strength Clause 5.2		10 kV			
		Abnormal operating and fault conditions		240 V			
		Clause 5.3 Transformers Clause 5.3.3 Functional insulation Clause 5.3.4			00 mm er Caliper		

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	INFORMATION TECHNOLOGY EQUIPMENT	Audio amplifiers in information technology equipment Clause 5.3.6	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010		Hz to 1.5 Ghz to 150°C & ± 0.2°C		
		During the tests Clause 5.3.9.1 After the tests Clause 5.3.9.2		10	kV		
		Separation of the telecommunication network from earth		10	kV		
		Clause 6.1.2 6.1.2.1		0 to	o 200 mm		
		Separation requirements Clause 6.2.1			mm $\pm 0.2$ mm long nted and rigid Finger,		
					04 mm long st Probe		
				10	kV		
					o 200 mm rnier Caliper		
		Steady-state test Clause 6.2.2.2		10	kV		

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	INFORMATION TECHNOLOGY EQUIPMENT	Protection of cable distribution system service persons, and users of other equipment connected to the system, from hazardous voltages in the equipment Clause 7.2 Protection of equipment users from over voltages on the cable distribution system Clause 7.3	IEC 60950-1:2005 A:2013 IS 13252 (Part1):2010	80 jo 80 pr 44 10	30 V 0 mm ±0.2 mm long ointed and rigid Finger, 0 mm ±0.2 mm long robe 4.04 mm long 0 kV to 200 mm ernier Caliper			
2.	AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	Conduct of test Clause 4.1, 4.1.4 Normal operating condition Clause 4.2 (excluding 4.2.4) Fault conditions Clause 4.3	IS 616:2010 IEC 60065:2001+ A1: 200:	5 (b 24 11 (s 22 11 (s 24 11 -4 20	cm space, 5cm depth box) 40V kHz to 1.5Ghz ignal gen) 40V kHz 40 to 150°C & $\pm$ 0.2°C 20 g/m <sup>2</sup> density (paper) 0° to 60°			

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AND SIMILA ELECTRON	AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	Marking and general requirement Clause 5.0 to 5.4	IS 616:2010 IEC 60065:2001+ A1: 2005	n-]	etroleum spirit or hexane, water, ece of cloth		
		Heating under normal operating conditions Clause 7 (7.1 to 7.2)		1k	40V xHz to 1.5Ghz 0 to 150 °C & ± 0.2°C		
		Construction requirements with		10	) kV		
		regard to the protection against electric shock Clause 8			0 to 98 %RH 0°C to +150°C		
		(8.2,8.3,8.6,8.8, 8.9,8.10,8.11, 8.13,8.14,8.15,8.18			200mm, least count 01mm		
				-Fi - a -du -sv ap oc	ange:- req. :10-150-10Hz amplitude: 0 to 25 mm uration: 1sec to 75 min weep rate: pproximately one stave per minute DN, 50N, 2N		

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	AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	noi Cla 9.1	ctric shock hazard under mal operating condition nuse 9.1.1, 9.1.1.1, 9.1.1.2, .2, 9.1.3, 9.1.4, 9.1.5, 9.1.6, .7, 9.2	IS 616:2010 IEC 60065:2001+ A1: 200:	5	AC Vo wave) 200V, DC Cu 200mA AC Cu Sine w 200mA Resista 20kΩ, 20 MΩ Freque wave)- 2 mA ( 80 mm jointed Probes 44.04 n 15 mm 100 mm 2.5mm 100 mm 5 mm 1 8 mmv	arrent- 20mA, A, 10A arrent (50Hz, ave)- 20mA, A, 10A ance : 200 Ω, 2 kΩ, 200 kΩ, 2MΩ, 200 kΩ, 2MΩ, 20 kHz, 200 kHz (touch current) $\pm$ 0.2 mm long H Finger $\pm$ 58.04 mm long mm long $\pm$ 0.0, -0.1 Pin diameter, m length diameter, m length a diameter, h length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length length, length, length length, length, length, length length, length length, length, length length, length, length length, length, length length, length length, len

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S.No. Product / Material of Test	Specific Test Performed	Test Method Specificat against which tests are performed		ange of Testing / imits of Detection	
AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	Insulation requirement Clause 10.2,10.3.1,10.3.2	IS 616:2010 IEC 60065:2001+ A1: 2005	5 -4	0 to 98 %RH 40°C to +150°C 00 MΩ (IR) 0kV	
	Fault conditions Clause 11.1, 11.2, 11.2.3, 11.2.4, 11.2.5, 11.2.6		2 A w 2 D 2 A w 1 C 2 A W 1 C 2 C F W 2 2 F F 4 1 1 1 1 1 2	PC Voltage- 200mV, 2V, 0V, 200V, 1000V C Voltage- (50Hz, Sine vave) 200mV, 2V, 20V, 00V, 750V PC Current- 20mA, 00mA, 10A C Current (50Hz, Sine vave)- 20mA, 200mA, 0A esistance -200 $\Omega$ , 2k $\Omega$ , $0k\Omega$ , 200 k $\Omega$ , 2M $\Omega$ , $0M\Omega$ requency (3 volt, sine vave)- 20kHz, 200 kHz 40 to 150 °C & ± 0.2°C mA (touch current) robes: 58.04 mm long 4.04 mm long 5mm+0.0, -0.1 Pin mm diameter, 00mm length .5mm diameter, 00mm length .5mm diameter, 00mm length	

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rd ISO/IEC 17025: 2005			
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Specific Test Performed			ige of Testing / its of Detection
Fault conditions Clause 11.1, 11.2, 11.2.3, 11.2.4, 11.2.5, 11.2.6 Mechanical strength Clause 12.1, 12.1.1, 12.1.2, 12.1.3, 12.1.4, 12.1.5, 12.2, 12.4, 12.6, 12.6.1	IS 616:2010	5 80m 5 80m 2501 Voc heig Ran, -Fre - am -dur -swe appr octa (vib: $0.22(spri500g(steeHardplyvthicl20 to-40°(env2cN40cl4Nn$	q. :10-150-10Hz pplitude: 0 to 25 mm ation: 1 sec to 75min eep rate: oximately one ve per minute ration) J to 1J ing hammer) gm,50mm diameter el ball) dwood 13 mm thick, wood 19 to 20mm c (drop) o 95% RH C to +150°C Temp. - chamber) m to 30 cNm Nm to 300 cNm n to 10Nm (torque)
	RIICO Bhamashah Ind d ISO/IEC 17025: 2005 Electronics Testing T-2698 - Specific Test Performed Fault conditions Clause 11.1, 11.2, 11.2.3, 11.2.4, 11.2.5, 11.2.6 Mechanical strength Clause 12.1, 12.1.1, 12.1.2, 12.1.3, 12.1.4, 12.1.5, 12.2, 12.4,	RIICO Bhamashah Industrial Area, Kaladwas,rdISO/IEC 17025: 2005Electronics TestingT-2698-Specific Test PerformedTest Method Specificat against which tests are performedFault conditionsIS 616:2010 IEC 60065:2001+ A1: 2005Fault conditionsIS 616:2010 IEC 60065:2001+ A1: 2005Mechanical strength Clause 12.1, 12.1.1, 12.1.2, 12.1.3, 12.1.4, 12.1.5, 12.2, 12.4,	RIICO Bhamashah Industrial Area, Kaladwas, Udaipur, R         d       ISO/IEC 17025: 2005         Electronics Testing       Issue Date         T-2698       Valid Unti         -       Page         Specific Test Performed       Test Method Specification against which tests are performed       Rar         Fault conditions       IS 616:2010       12 n         Clause 11.1, 11.2, 11.2,3, 11.2.4, 112.6       IS 616:2001 + A1: 2005       80m         Mechanical strength       Woot       12 n       -         Clause 12.1, 12.1.1, 12.1.2, 12.2, 12.4, 12.6, 12.6, 1       -       -       -         Mechanical strength       Woot       Woot       -       -         Vib O, 12.2, 12.6, 12.6, 1       -       -       -       -         Valid Unti       -       -       -       -       -         Valid Conditions       IS 616:2010       12 n       -

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S.No. Product / Material of Test	Specific Test Performed	Test Method Specificati against which tests are performed		e of Testing / s of Detection
AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	Clearance and creepage distance Clause 13.3.1, 13.3.2, 13.3.3, 13.5, 13.6, 13.7,13.8	IS 616:2010 IEC 60065:2001+ A1: 2005	5 0.01m (verni 2V, 20 AC V wave) 200V, DC C 200m AC C wave) 10A Resist 20kΩ, 20MΩ Frequ wave) 80 mm jointed	er) oltage- 200mV, 0V, 200V, 1000V oltage- (50Hz, Sine 200mV, 2V, 20V, , 750V urrent- 20mA, A, 10A urrent (50Hz, Sine - 20mA, 200mA, ance -200Ω, 2k Ω, , 200 kΩ, 2MΩ,

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S.No.	Product / Material of Test	Sp	ecific Test Performed	Test Method Specificat against which tests are performed			e of Testing / s of Detection	
	AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	Cla	rminals use 15.1,15.2, 15.3.2,15.3.5, 3.6,15.3.7,15.4.3	IS 616:2010 IEC 60065:2001+ A1: 200	5	(micro 5N 0 to 20 0.01mi 2cNm 40cNm 4Nm to Hardw plywoo thick ( 40N to DC Vo 2V, 20 AC Vo wave) 200V, DC Cu 200m/ AC Cu wave)- 10A Resista 20kQ, 20MQ Freque	00 mm, least count m (vernier) to 30 cNm a to 300 cNm o 10Nm (torque) rood 13 mm thick, od 19 to 20mm drop) 0 70N (weight) oltage: 200mV, W, 200V, 1000V oltage- (50Hz, Sine 200mV, 2V, 20V, 750V urrent- 20mA, A, 10A urrent (50Hz, Sine - 20mA, 200mA, ance: 200 $\Omega$ , 2k $\Omega$ , 200 k $\Omega$ , 2M $\Omega$ ,	

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	on Rang Limit	e of Testing / s of Detection			
	AUDIO & VIDEO AND SIMILAR ELECTRONIC APPARATUS	External flexible cord Clause 16.2,16.3,16.4,16.5	IS 616:2010 IEC 60065:2001+ A1: 2005	(micro 10kV -40 to	e: 0-25mm o meter) 150 °C & ± 0.2°C 1.5Ghz l gen)			
		Electrical connections and mechanical fixings Clause 17.1,17.2,17.3,17.4		40 cN 4 Nm- 12 mn 80 mn	n-30 cNm m-300 cNm -10 Nm n diameter, n length length, width			
		Ageing Process Clause 18.2.1			98 % RH to +150°C			
		Stability and mechanical hazards Clause 19.1,		10°an	gle (inclined plane)			
		19.2,19.3,19.4,19.5,19.6		100 N	(weight)			
					mm, least count nm (vernier)			

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S.No.	Product /	Specific Test Performed	Test Method Specification	Range of Testing /
	Material of Test		against which tests are	Limits of Detection
			performed	

## **III. SAFETY TESTING**

1.	SAFETY REQUIREMENTS FOR ELECTRICAL	Marking (Clause 5.1) Identification (Clause 5.1.2)	IEC 61010-1:2010	240V
	EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE	Mains supply (Clause 5.1.3) Fuses (Clause 5.1.4) Terminals, connections and operating devices Clause 5.1.5 Switches and circuit breakers Clause 5.1.6		
		Equipment protected by Double Insulation or Reinforced Insulation (Clause 5.1.7)		
		Warning marking Clause 5.2		0-200mm Vernier calliper
		Durability of marking Clause 5.3		Qualitative test
		Documentation Clause 5.4		-

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE	Protection against electric shock Clause 6 General Clause 6.1 Determination of ACCESSIBLE parts Clause 6.2 Limit values for ACCESSIBLE parts Clause 6.3 Primary means of protection Clause 6.4	IEC 61010-1:2010	<ul> <li>80 mm ±0.2 mm long jointed and rigid Finger 100 mm long, 4 mm diameter test pin 100 mm long, 4 mm diameter test pin</li> <li>0.5mA to 2mA</li> <li>0-200mm Vernier Caliper DC Voltage- 200mV, 2V, 20V, 200V, 1000V AC Voltage- (50Hz, Sine wave) 200mV, 2V, 20V, 200V, 750V DC Current- 20mA,</li> </ul>
				<ul> <li>200mA, 10A</li> <li>AC Current (50Hz, Sine wave)- 20mA, 200mA, 10A</li> <li>Resistance -200Ω, 2k Ω, 20kΩ, 200 kΩ, 2MΩ, 20MΩ</li> <li>Frequency (3 volt, sine wave)- 20kHz, 200 kHz</li> </ul>

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	SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE	Additional means of Protection in case of SINGLE FAULT CONDITION Clause 6.5	IEC 61010-1:2010	2cNm 40cNn 4Nm-1 DC Va 2V, 20 AC Va (50Hz 200m 750V DC Cu 20mA AC Cu (50Hz 20mA AC Cu (50Hz 20mA Resista 200Ω, kΩ, 2N Freque (3 volt	a, 200mA, 10A urrent $\alpha$ , Sine wave)- $\alpha$ , 200mA, 10A ance – $\beta$ , 2k Ω, 20kΩ, 200 MΩ, 20MΩ		

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SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE	Connections to external circuits Clause 6.6 Insulation requirements Clause 6.7	IEC 61010-1:2010	jointed 100 m diamet 100 m diamet DC Vo 2V, 20 AC Vo wave) 200V, DC Cu 200m AC Cu wave)- 10A Resista 20k $\Omega$ , 20M $\Omega$ Freque wave)- 0-200r	urrent- 20mA, A, 10A urrent (50Hz, Sine - 20mA, 200mA, ance -200Ω, 2k Ω, 200 kΩ, 2MΩ, 200 kΩ, 2MΩ, ency (3 volt, sine - 20kHz, 200 kHz		

10kV

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S.No. Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed		e of Testing / s of Detection		
SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE	Constructional requirements for protection against electric shock Clause 6.9	IEC 61010-1:2010	20 to 9 0-200 Vernie Torqu 2cNm 40cNr 4Nm- Force 0.01N Force 0.01N Torqu 2 cNn 40 cN 4 Nm- 0-200	er Caliper -30 cNm -300 cNm 10Nm Gauge -196N Gauge -196N e Screw Driver 1-30 cNm m-300 cNm 10 Nm		
			250 N 10°ang	$\pm 10$ N		

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specificat against which tests are performed		nge of Testing / hits of Detection			
	SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE	Resistance to mechanical stresses Clause 8 Equipment Temperature Limits and Resistance to Heat Clause 10 Protection by interlocks Clause 15	IEC 61010-1:2010	500 Har Ten 38°0 20 t -40° 20N 80 r join	f hard rod g $\pm 25$ g steel ball dwood board nperature sensor - C to $+150$ °C o 98 %RH °C to $+150$ °C f Ball Pressure setup nm $\pm 0.2$ mm long ted test Finger rlock reliability setup			
		Hazards resulting from application Clause 16 RISK assessment (Clause 17)			00 cycles			